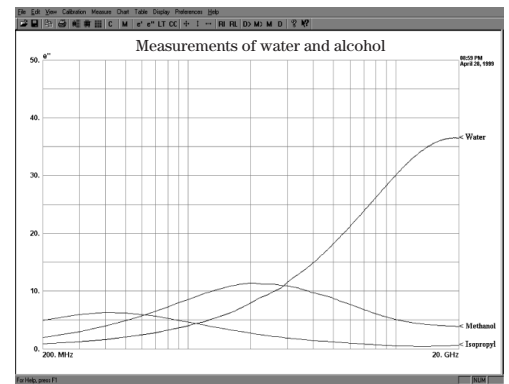
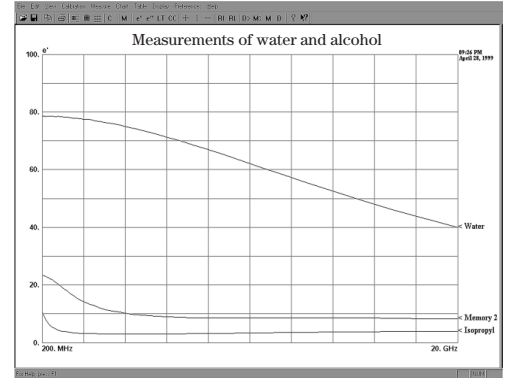
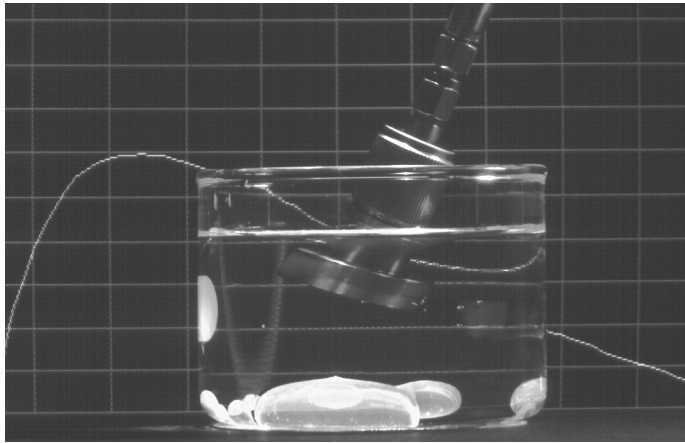


HP

85070C

Dielectric Probe Kit

200 MHz to 20 GHz



Software displays dielectric constant and loss factor across a 200 MHz to 20 GHz frequency sweep.

New Features of HP 85070C

- Compatible with Windows® 95, 98, or NT 4.0
- Compatible with HP economy network analyzers, HP 8712ET/ES, HP 8714ET/ES
- Addition of markers
- Split screen view showing simultaneous plot and listing of data
- Ability to copy/paste menu items to other applications in plot or list format
- Support of additional IEEE-488 interface cards: HP 82340, 82341, 82350
- On-line manual

Swept high-frequency dielectric measurements

The HP 85070C is a dielectric probe that is used to measure the intrinsic electrical properties of materials in the RF and microwave frequency bands.

The HP 85070C software allows you to measure the complex dielectric constant (also called relative permittivity, or ϵ_r) of liquids and semi-solids, including the dielectric loss factor or loss tangent.

To obtain data at hundreds of frequencies in seconds, simply immerse the probe into liquids or semi-solids—no special fixtures or containers are required. For pliable solids (such as plastics), just press the probe against a flat surface.

The HP 85070C must be used in conjunction with an HP network analyzer. The network analyzer provides the high frequency stimulus, and measures the reflected response.

The probe transmits a signal into the material under test (MUT). The measured reflected response from the material is then related to its dielectric properties. A computer controls the system, and runs software that guides the user through a measurement sequence (computer not included in HP 85070C).

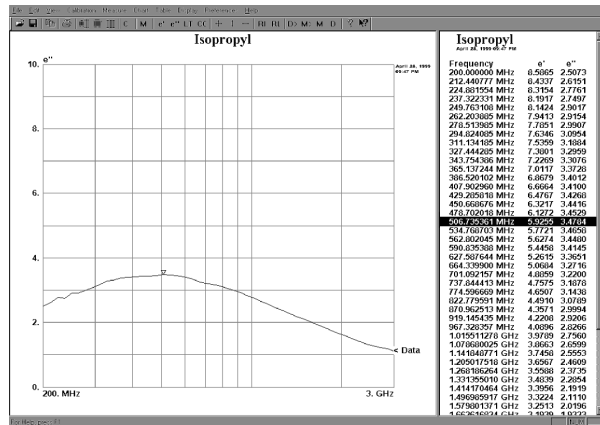
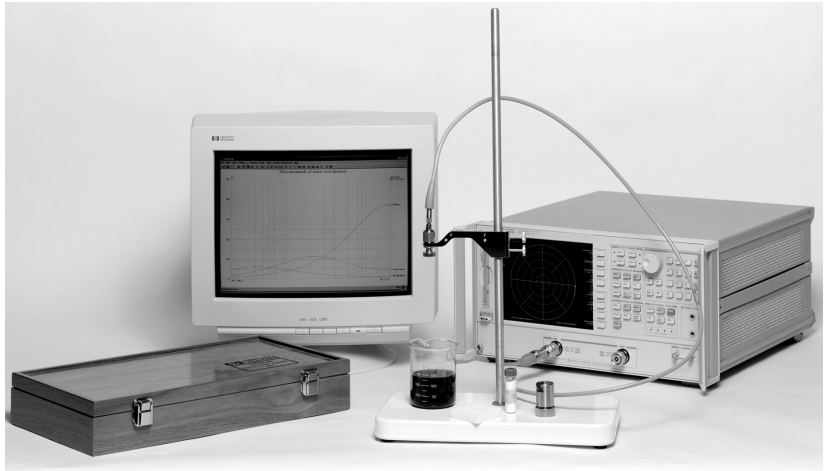
HP 85070C measurement attributes

- Rugged design withstands temperatures from -40° to $+200^\circ$ C.
- Hermetic glass-to-metal seal resists corrosive chemicals.
- Refresh calibration simplifies measurements over temperature.
- Accessories (cable, short circuit, mounting bracket) improve measurement repeatability.

Probe survives corrosive chemicals or high temperatures

The probe features a hermetic glass-to-metal seal, which makes it resistant to corrosive or abrasive chemicals.

The probe withstands a wide -40°C to $+200^{\circ}\text{C}$ temperature range, which allows measurements versus frequency and temperature. This is an important variable, since the dielectric constant of a material can vary significantly as a function of temperature.



Split screen window and marker aids in data analysis. Simply click on a point on the chart or list to activate the marker.

A special refresh calibration feature provides corrected measurements over a wide temperature range. Rather than doing a full calibration at each temperature, a single standard can be used to update or refresh an existing calibration.

Contents of HP 85070C high-temperature dielectric probe kit

High-temperature dielectric probe	3.5 mm (m) connector type
Dielectric probe software	Windows 95, 98, NT 4.0
Flexible cable	Connects probe to network analyzer test port; 1 meter long with SMA (f) to SMA (f) connectors.
High-temperature cable (Option 002)	1 meter long semi-rigid high-temperature (-40° to $+200^{\circ}\text{C}$) cable with SMA (f) to SMA (f) connectors.
Adapters	Adapts network analyzer test port to flexible cable, when necessary; includes one 3.5 mm (m) to 7 mm adapter for 7 mm test ports and one 3.5 mm (m) to Type-N (m) adapter for Type-N (f) test ports.
50 Ω termination	Used for open/short/load calibrations; 3.5 mm (m) connector type.
Shorting block and clamp	Fits over probe face for a repeatable short circuit.
Remote trigger switch and cable	Allows hands-free or remote measurements; 2 meter long cable connects to HP 8752, 8753, 8719, 8720 and 8722 network analyzers.
Mounting bracket	Keeps probe in a fixed position to minimize cable movement for more repeatable measurements; bracket fits a 1/2-inch diameter support rod.
Probe stand (Option 001)	Probe stand consists of a 24-inch high, 1/2-inch diameter metal support rod with a 13x7-inch porcelain base.
Liquid vials (2) with stoppers and adapter	For measurements of liquids; 15 ml volume.

Performance Characteristics

Specifications describe the warranted performance over the temperature range 0° to 55° C. Supplemental characteristics are intended to provide information useful in applying the instrument, by giving typical but non-warranted performance parameters. These are denoted as “typical,” “nominal,” or “approximate.”

Frequency range

Probe: 200 MHz to 20 GHz (nominal)

Maximum limited by MUT properties: $< \frac{110}{\sqrt{|\epsilon_r^*|}} \text{GHz}$

Temperature

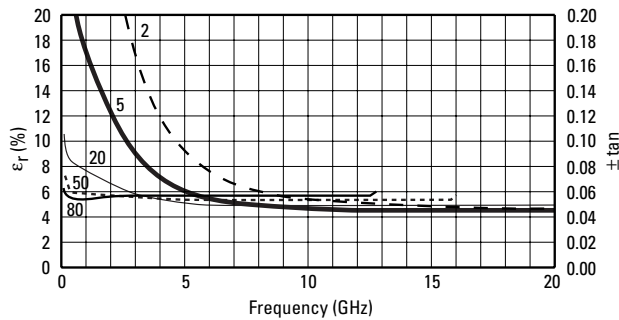
Range: -40° C to +200° C

Rate: <10° C per minute

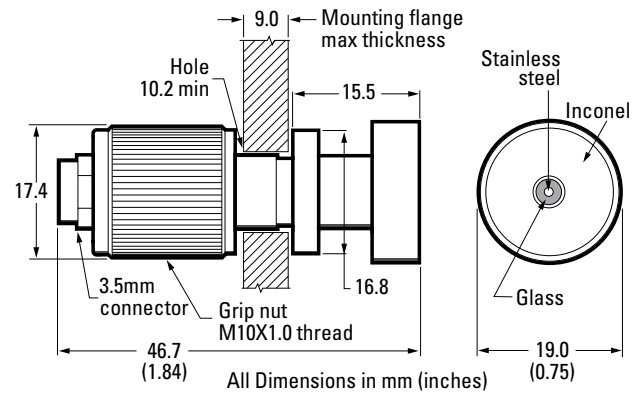
Accuracy (typical)

Dielectric constant, ϵ_r^* : $\pm 5\%$

Loss tangent, $\tan \delta$, $\epsilon_r^*/\epsilon_r^*$: ± 0.05



Typical accuracy¹ vs. frequency for $\epsilon_r^* = 2, 5, 20, 50, 80$



Repeatability and resolution (typical)

Two to four times better than accuracy.

Material under test assumptions

Material is “infinite” in size, non-magnetic ($\mu_r^* = 1$), isotropic (uniform orientation), and homogeneous (uniform composition)². Solids have a single, smooth, flat³ surface with gap-free contact at the probe face.

Sample requirements

Diameter: > 20 mm

Thickness: $> \frac{20}{\sqrt{|\epsilon_r^*|}} \text{mm}$

Granule size⁴: < 0.3 mm

Maximum recommended ϵ_r^* : < 100

Minimum recommended $\tan \delta^5$: > 0.05

1. Practical frequency range, accuracy and resolution depend on properties of the MUT. Graphs indicate typical accuracy at $23 \pm 3^\circ \text{C}$, not including effects of probe contact and cable flexure.
2. If the material is not homogeneous, the result is an average value weighted by the intensity of the E-field which is highest at the center conductor of the probe tip.
3. Sample must be as flat as the probe face which is lapped to $\pm 100 \mu \text{inches}$.
4. Measurement repeatability for granular materials is dependent on density variation.
5. Not recommended for low loss ($\tan \delta < 0.5$) materials with $\epsilon_r^* > 5$.

Software Menu Items

File

Save or recall measurement setups or previous measurement results. Print copies of the measurement results in a tabular or graphical format.

Edit

Copy the measurement results to the clipboard. Either graph or the tabular listing can be copied. This allows your measurements results to be pasted into other applications.

View

Select the section you want to view. Selection include the toolbar, status bar, table of the measurement data and chart of the measurement data.

Calibration

Select the frequency range, number of points, linear or log sweep. Guided calibration sequence; choice of calibration materials or user-specified; refresh calibration for single standard; recalibration versus temperature.

Measure

Trigger a measurement.

Chart

Select the format to be displayed on the chart. Choices include ϵ_r' , ϵ_r'' , $\tan \delta$ and Cole-Cole. Set Graticule scale factors or "autoscale". Select from linear, semi-log or log-log representations.

Table

Choose between a tabular formatting of real and imaginary or real and $\tan \delta$.

Display

Display current measurement data; save/display up to 3 memory traces; compare data to reference trace with trace math. Turn the marker on or off.

Preferences

Select your preferences of fonts, colors and annotations used to plot and list the measurement data.

Help

On line help including the product manual.

ToolBar

Provides single click access to the most important menu items.

Ordering information

HP 85070C High-temperature dielectric probe kit
Kit includes probe, Windows 95, 98 or NT 4.0 compatible software, cable, adapters, termination, shorting block, probe bracket, remote trigger and vials. Not included, but required is a computer and network analyzer to complete the system.
(software supplied on CD-ROM)

Option 001 Adds probe stand (highly recommended)

Option 002 Adds high temperature cable

Option 070 Windows 95, 98 or NT 4.0 upgrade software
(upgrade from any version of HP 85070 software)

Option 300 Substitutes HP 85070B HP Basic software.
This option is EXACTLY THE SAME as HP 85070B Option 300.
This option supplies the software in HP Basic language (revision 1.05), instead of Windows.

Option 370 HP Basic software upgrade to HP 85070B
This option is EXACTLY THE SAME as HP 85079B Option 370. This option upgrades the HP Basic software to the latest revision available in HP Basic (revision 1.05).

Note on HP Basic version of software:

We will continue to offer the software in the HP Basic language, as Option 300, or Option 370. However, the HP Basic software does not have the full functionality of the new Windows version. Furthermore, the HP Basic software was not upgraded from the B to the C models. So even though you may order HP 85070C Option 300 or 370, you will receive HP 85070B software.

The difference between Options 300 and 370:

Option 300 supplies the software in HP Basic language.

Option 370 upgrades the previous HP Basic revision to the latest HP BASIC revision.

Additional available parts

8710-2036 High temperature dielectric probe

1810-0118 50 ohm SMA male termination

85070-60003 Shorting block and clamp



Compatible network analyzers

HP 8752A/C	300 kHz to 1.3 or 3 GHz
HP 8753A/B/C/D/E	30 kHz to 3 or 6 GHz
HP 8719A/C/D	50 or 130 MHz to 13.5 GHz
HP 8720A/B/C/D	50 or 130 MHz to 20 GHz
HP 8722A/C/D	50 MHz to 40 GHz
HP 8712ET/ES	300 kHz to 1.3 GHz
HP 8714ET/ES	300 kHz to 3 GHz
HP 8712B/C	300 kHz to 1.3 GHz
HP 8714B/C	300 kHz to 3 GHz
HP 8510B/C	45 MHz to 110 GHz

PC requirements

- Windows 95, 98 or NT 4.0 or higher
- Compatible IEEE-488 interface cards:
 - HP 82335, 82340, 82341, 82350, National Instrument Cards
- CD-ROM drive

For more information about Hewlett-Packard test and measurement products, applications, services, and for a current sales office listing, visit our web site, <http://www.hp.com/go/tmdir>. You can also contact one of the following centers and ask for a test and measurement sales representative.

United States:

Hewlett-Packard Company
Test and Measurement Call Center
P.O. Box 4026
Englewood, CO 80155-4026
1 800 452 4844

Canada:

Hewlett-Packard Canada Ltd.
5150 Spectrum Way
Mississauga, Ontario L4W 5G1
(905) 206 4725

Europe:

Hewlett-Packard
European Marketing Centre
P.O. Box 999
1180 AZ Amstelveen
The Netherlands
(31 20) 547 9900

Japan:

Hewlett-Packard Japan Ltd.
Measurement Assistance Center
9-1, Takakura-Cho, Hachioji-Shi,
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